Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination BARRETT ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0083206 A1	06-2002	Volpano, Dennis Michael	709/249
*	В	US-2003/0064718 A1	04-2003	Haines et al.	455/423
*	С	US-2003/0125019 A1	07-2003	Bajikar, Sundeep M.	455/420
*	D	US-2004/0122985 A1	06-2004	Parra et al.	710/001
*	E	US-2004/0137925 A1	07-2004	Lowe et al.	455/509
*	F	US-2004/0160957 A1	08-2004	Coffman, Stephen Blaine	370/394
*	G	US-2004/0170181 A1	09-2004	Bogdon et al.	370/400
*	Н	US-2004/0236856 A1	11-2004	Keohane et al.	709/229
*	1	US-7,136,904 B2	11-2006	Bartek et al.	709/217
*	J	US-7,154,877 B2 .	12-2006	Le et al.	370/346
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q				,	
	R					
	S					
	Т			,		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.